

**• General Description**

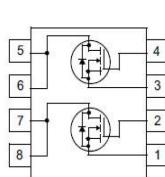
The CH20N06SN combines advanced trench MOSFET technology with a low resistance package to provide extremely low  $R_{DS(ON)}$ . This device is ideal for load switch and battery protection applications.

**• Features**

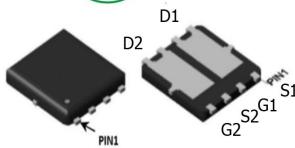
- Advance high cell density Trench technology
- Low  $R_{DS(ON)}$  to minimize conductive loss
- Low Gate Charge for fast switching
- Dual DIE in one package

**• Application**

- Power Management in Notebook Computer,
- Portable Equipment and Battery Powered Systems

**• Product Summary**


$V_{DS1} = 60V$   
 $V_{DS2} = 60V$   
 $R_{DS(ON)1} = 26 m\Omega$   
 $R_{DS(ON)2} = 26 m\Omega$   
 $I_D1 = 20A$   
 $I_D2 = 20A$



PDFN3\*3

**• Ordering Information:**

Part NO.	CH20N06SN
Marking	CH20N06SN
Packing Information	REEL TAPE
Basic ordering unit (pcs)	5000

**• Absolute Maximum Ratings ( $T_c = 25^\circ C$ )**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$I_D@T_c=25^\circ C$	20	A
	$I_D@T_c=75^\circ C$	13	A
	$I_D@T_c=100^\circ C$	13	A
Pulsed Drain Current <sup>①</sup>	$I_{DM}$	80	A
Total Power Dissipation( $T_c=25^\circ C$ )	$P_D@T_c=25^\circ C$	22.7	W
Total Power Dissipation( $T_A=25^\circ C$ )	$P_D@T_A=25^\circ C$	0.69	W
Operating Junction Temperature	$T_J$	-55 to 150	$^\circ C$
Storage Temperature	$T_{STG}$	-55 to 150	$^\circ C$
Single Pulse Avalanche Energy	$E_{AS}$	27	mJ

**•Thermal resistance**

Parameter	Symbol	Min.	Typ.	Max.	Unit
Thermal resistance, junction - case	R <sub>thJC</sub>	-	-	2.5	° C/W
Thermal resistance, junction - ambient	R <sub>thJA</sub>	-	-	70	° C/W
Soldering temperature, wavesoldering for 10s	T <sub>sold</sub>	-	-	265	° C

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250uA	60			V
Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	1.0	1.6	2.5	V
Drain-Source Leakage Current	I <sub>DS</sub>	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V			1.0	uA
Gate- Source Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V ,V <sub>DS</sub> =0V			±100	nA
Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =20A		26	33	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =10A		33	45	mΩ
Forward Transconductance	g <sub>FS</sub>	V <sub>DS</sub> =25V, I <sub>D</sub> =10A		19		s
Source-drain voltage	V <sub>SD</sub>	I <sub>S</sub> =20A			1.20	V

**•Electronic Characteristics**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Input capacitance	C <sub>iss</sub>	f = 1MHz	-	860	-	pF
Output capacitance	C <sub>oss</sub>		-	62	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	51	-	

**•Gate Charge characteristics(T<sub>a</sub> = 25°C)**

Parameter	Symbol	Condition	Min.	Typ	Max.	Unit
Total gate charge	Q <sub>g</sub>	V <sub>DD</sub> = 25V ID = 5A V <sub>GS</sub> = 10V	-	20.3	-	nC
Gate - Source charge	Q <sub>gs</sub>		-	3.7	-	
Gate - Drain charge	Q <sub>gd</sub>		-	5.3	-	

Notes 1.Repetitive Rating: Pulse width limited by maximum junction temperature.

 Notes 2.E<sub>AS</sub> condition: T<sub>J</sub>=25°C, V<sub>DD</sub>=15V, V<sub>G</sub>=10V, R<sub>G</sub>=25Ω, L=0.5mH.

Notes 3.Repetitive Rating: Pulse width limited by maximum junction temperature.

### Typical Performance Characteristics

Figure 1: Output Characteristics

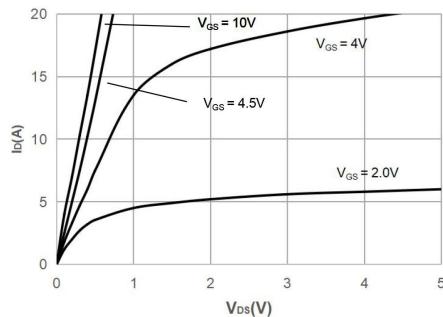


Figure 2: Typical Transfer Characteristics

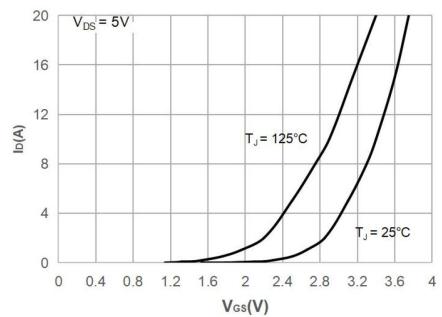


Figure 3: On-resistance vs. Drain Current

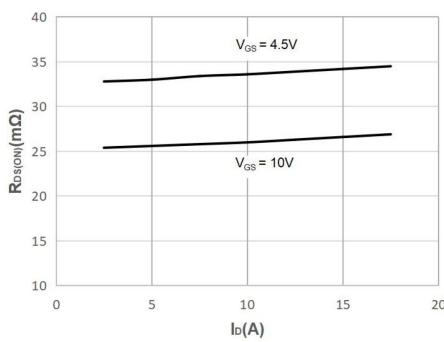


Figure 4: Body Diode Characteristics

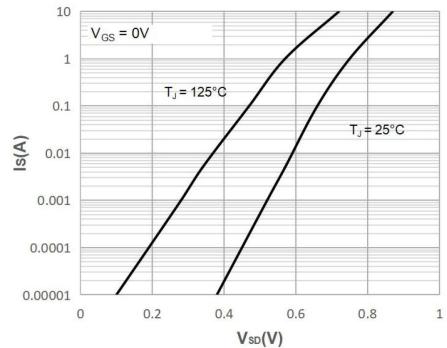


Figure 5: Gate Charge Characteristics

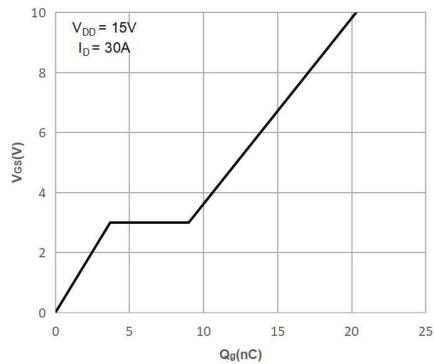
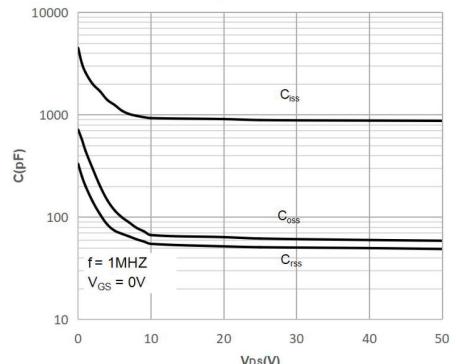
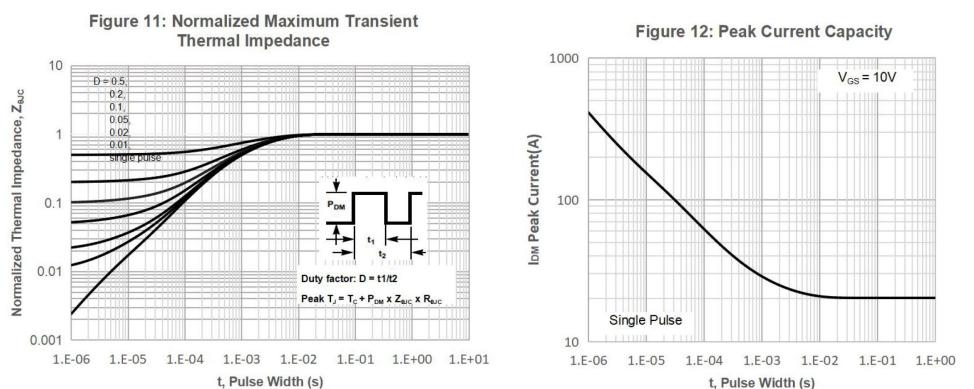
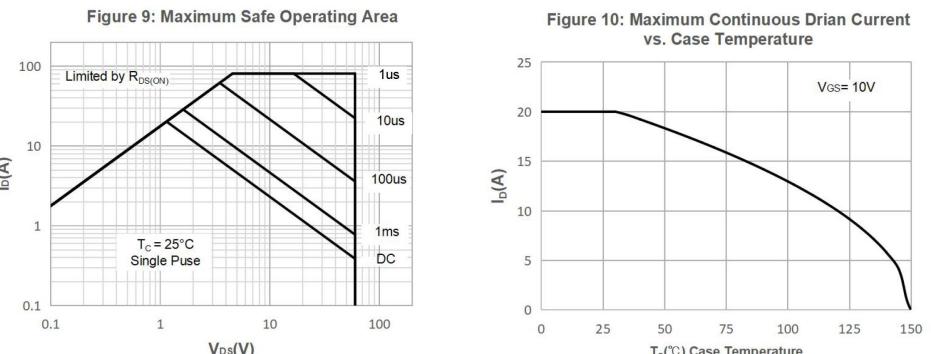
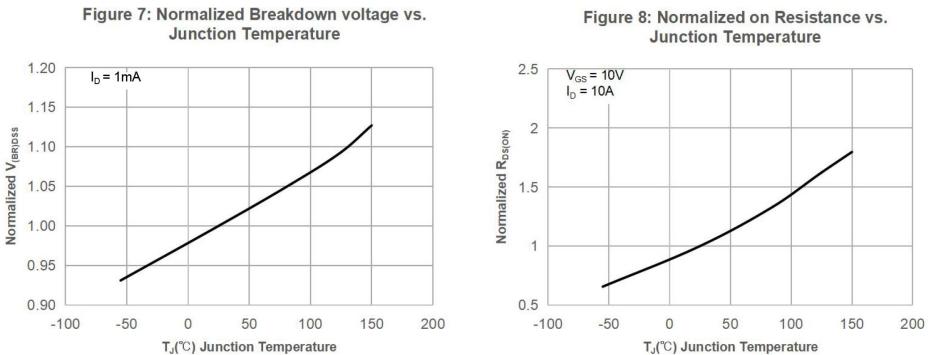


Figure 6: Capacitance Characteristics



## Typical Performance Characteristics



### Test Circuit

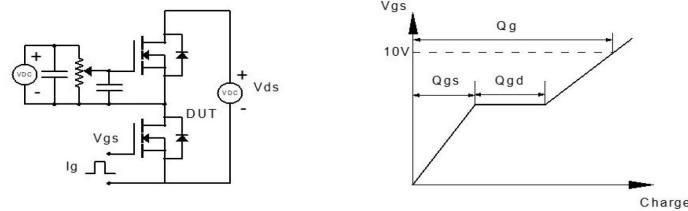


Figure 1: Gate Charge Test Circuit & Waveform

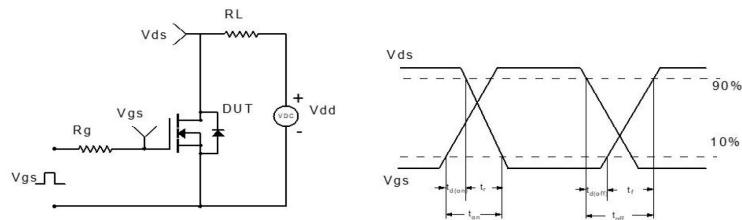


Figure 2: Resistive Switching Test Circuit & Waveform

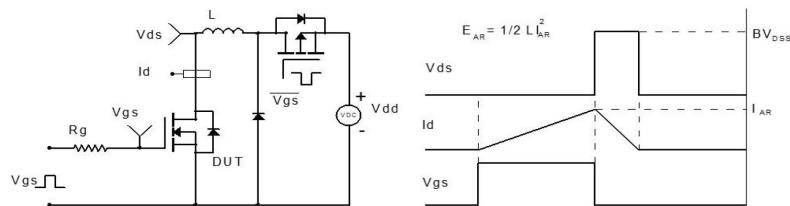


Figure 3: Unclamped Inductive Switching Test Circuit & Waveform

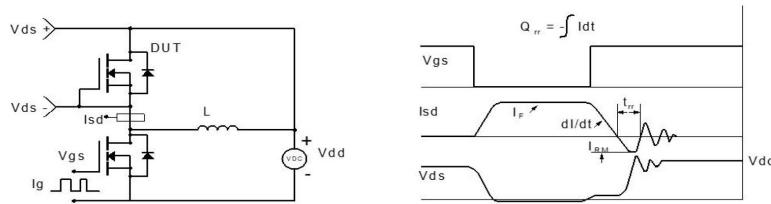


Figure 4: Diode Recovery Test Circuit & Waveform

**•Dimensions(DFN3\*3)**

Unit: mm

<i>A</i>	0.70	0.75	0.80
<i>b</i>	0.25	0.30	0.35
<i>c</i>	0.10	0.15	0.25
<i>D</i>	3.25	3.35	3.45
<i>D1</i>	3.00	3.10	3.20
<i>D2</i>	1.78	1.88	1.98
<i>D3</i>	---	0.13	---
<i>E</i>	3.20	3.30	3.40
<i>E1</i>	3.00	3.15	3.20
<i>E2</i>	2.39	2.49	2.59
<i>e</i>	0.65BSC		
<i>H</i>	0.30	0.39	0.50
<i>L</i>	0.30	0.40	0.50
<i>L1</i>	---	0.13	---
<i>K</i>	0.30	---	---
$\theta$	---	10°	12°
<i>M</i>	*	*	0.15

